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UICC-Terminal interface;  
Physical, electrical and logical test specification;  
Part 1: Terminal features  
(Release 13)**

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# Contents

Intellectual Property Rights .....	12
Foreword.....	12
Modal verbs terminology.....	12
Introduction .....	13
1 Scope .....	14
2 References .....	14
2.1 Normative references .....	14
2.2 Informative references.....	15
3 Definition of terms, symbols, abbreviations and coding conventions.....	15
3.1 Terms.....	15
3.2 Symbols.....	15
3.3 Abbreviations .....	16
3.4 Coding conventions.....	17
3.5 Applicability.....	17
3.5.1 Applicability of the present document.....	17
3.5.2 Applicability of the individual test cases .....	17
3.5.3 Applicability to terminal equipment .....	17
3.6 Definitions.....	17
3.6.1 Format of table of the table of optional features.....	17
3.6.2 Format of the applicability table.....	17
3.6.3 Status and Notations .....	18
3.7 Table of optional features.....	18
3.8 Applicability table .....	19
4 Physical characteristic tests .....	23
4.1 Contact pressure .....	23
4.1.1 Definition and applicability .....	23
4.1.2 Conformance requirement .....	23
4.1.2.0 Description.....	23
4.1.2.1 Reference .....	23
4.1.3 Test purpose.....	23
4.1.4 Method of test.....	23
4.1.4.1 Initial conditions .....	23
4.1.4.2 Procedure .....	23
4.1.5 Acceptance criteria .....	23
4.2 Curvature of the contacting elements .....	23
4.2.1 Definition and applicability .....	23
4.2.2 Conformance requirement .....	24
4.2.2.0 Description.....	24
4.2.2.1 Reference .....	24
4.2.3 Test purpose.....	24
4.2.4 Method of test.....	24
4.2.4.1 Initial conditions .....	24
4.2.4.2 Procedure .....	24
4.2.5 Acceptance criteria .....	24
5 Electrical characteristic tests .....	24
5.1 Test of the power transition phases .....	24
5.1.1 Phase preceding Terminal power on.....	24
5.1.1.1 Definition and applicability.....	24
5.1.1.2 Conformance requirement.....	24
5.1.1.3 Reference .....	24
5.1.1.4 Test purpose .....	25
5.1.1.5 Method of test .....	25
5.1.1.5.1 Initial condition .....	25

5.1.1.5.2	Procedure.....	25
5.1.1.6	Acceptance criteria.....	25
5.1.2	Phase during UICC power on .....	25
5.1.2.1	Phase during UICC power on: 3 V - 5 V .....	25
5.1.2.1.1	Definition and applicability .....	25
5.1.2.1.2	Conformance requirement .....	25
5.1.2.1.3	Reference.....	25
5.1.2.1.4	Test purpose .....	26
5.1.2.1.5	Method of test.....	26
5.1.2.1.6	Acceptance criteria .....	26
5.1.2.2	Phase during UICC power on: 1,8 V - 3 V .....	26
5.1.2.2.1	Definition and applicability .....	26
5.1.2.2.2	Conformance requirement .....	26
5.1.2.2.3	Reference.....	26
5.1.2.2.4	Test purpose .....	26
5.1.2.2.5	Method of test.....	27
5.1.2.2.6	Acceptance criteria .....	27
5.1.3	Phase during Terminal power off .....	27
5.1.3.1	Phase during Terminal power off: 3 V - 5 V.....	27
5.1.3.1.1	Definition and applicability .....	27
5.1.3.1.2	Conformance requirement .....	27
5.1.3.1.3	Reference.....	27
5.1.3.1.4	Test purpose .....	28
5.1.3.1.5	Method of test.....	28
5.1.3.1.6	Acceptance criteria .....	28
5.1.3.2	Phase during Terminal power off: 1,8 V - 3 V.....	28
5.1.3.2.1	Definition and applicability .....	28
5.1.3.2.2	Conformance requirement .....	28
5.1.3.2.3	Reference.....	29
5.1.3.2.4	Test purpose .....	29
5.1.3.2.5	Method of test.....	29
5.1.3.2.6	Acceptance criteria .....	29
5.1.4	Warm reset timing .....	29
5.1.4.1	Definition and applicability.....	29
5.1.4.2	Conformance requirement.....	29
5.1.4.2.0	Description .....	29
5.1.4.2.1	Reference.....	30
5.1.4.3	Test purpose .....	30
5.1.4.4	Method of test .....	30
5.1.4.4.1	Initial conditions.....	30
5.1.4.4.2	Procedure.....	30
5.1.4.5	Acceptance criteria.....	30
5.1.5	UICC type recognition and voltage switching .....	30
5.1.5.1	Reaction of 3 V technology Terminals on type recognition of 3 V technology UICCs.....	30
5.1.5.1.1	Definition and applicability .....	30
5.1.5.1.2	Conformance requirement .....	30
5.1.5.1.3	Reference.....	30
5.1.5.1.4	Test purpose .....	31
5.1.5.1.5	Method of test.....	31
5.1.5.1.6	Acceptance criteria .....	31
5.1.5.2	Reaction of 3 V technology Terminals on type recognition of 1,8 V technology UICCs.....	31
5.1.5.2.1	Definition and applicability .....	31
5.1.5.2.2	Conformance requirement .....	31
5.1.5.2.3	Reference.....	31
5.1.5.2.4	Test purpose .....	32
5.1.5.2.5	Method of test.....	32
5.1.5.2.6	Acceptance criteria .....	32
5.1.5.3	Reaction of 1,8 V technology Terminals on type recognition of 1,8 V technology UICCs.....	32
5.1.5.3.1	Definition and applicability .....	32
5.1.5.3.2	Conformance requirement .....	32
5.1.5.3.3	Reference.....	32
5.1.5.3.4	Test purpose .....	32

5.1.5.3.5	Method of test.....	33
5.1.5.3.6	Acceptance criteria .....	33
5.1.5.4	Reaction of 1,8 V technology Terminals on type recognition of 3 V technology UICCs .....	33
5.1.5.4.1	Definition and applicability .....	33
5.1.5.4.2	Conformance requirement .....	33
5.1.5.4.3	Reference.....	33
5.1.5.4.4	Test purpose .....	33
5.1.5.4.5	Method of test.....	34
5.1.5.4.6	Acceptance criteria .....	34
5.1.5.5	Void.....	34
5.1.5.6	Reaction of Terminals receiving no ATR .....	34
5.1.5.6.1	Reaction of Terminals receiving no ATR: 3 V - 5 V.....	34
5.1.5.6.2	Reaction of Terminals receiving no ATR: 1,8 V - 3 V.....	35
5.2	Electrical tests on each Terminal contact .....	36
5.2.1	Nominal test conditions .....	36
5.2.2	Electrical tests on contact C1 (Card power supply - VCC).....	36
5.2.2.1	Electrical tests on contact C1, Test 1: 3 V - 5 V .....	36
5.2.2.1.1	Definition and applicability .....	36
5.2.2.1.2	Conformance requirement .....	37
5.2.2.1.3	Reference.....	37
5.2.2.1.4	Test purpose .....	37
5.2.2.1.5	Method of test.....	37
5.2.2.1.6	Acceptance criteria .....	37
5.2.2.2	Electrical tests on contact C1, Test 2: 3 V - 5 V .....	37
5.2.2.2.1	Definition and applicability .....	37
5.2.2.2.2	Conformance requirement .....	37
5.2.2.2.3	Reference.....	38
5.2.2.2.4	Test purpose .....	38
5.2.2.2.5	Method of test.....	38
5.2.2.2.6	Acceptance criteria .....	40
5.2.2.3	Electrical tests on contact C1, Test 1: 1,8 V - 3 V .....	40
5.2.2.3.1	Definition and applicability .....	40
5.2.2.3.2	Conformance requirement .....	40
5.2.2.3.3	Reference.....	40
5.2.2.3.4	Test purpose .....	40
5.2.2.3.5	Method of test.....	40
5.2.2.3.6	Acceptance criteria .....	41
5.2.2.4	Electrical tests on contact C1, Test 2: 1,8 V - 3 V .....	41
5.2.2.4.1	Definition and applicability .....	41
5.2.2.4.2	Conformance requirement .....	41
5.2.2.4.3	Reference.....	41
5.2.2.4.4	Test purpose .....	41
5.2.2.4.5	Method of test.....	41
5.2.2.4.6	Acceptance criteria .....	43
5.2.3	Electrical tests on contact C2 (Reset - RST).....	43
5.2.3.1	Electrical tests on contact C2: 3 V - 5 V .....	43
5.2.3.1.1	Definition and applicability .....	43
5.2.3.1.2	Conformance requirement .....	43
5.2.3.1.3	Reference.....	43
5.2.3.1.4	Test purpose .....	43
5.2.3.1.5	Method of test.....	43
5.2.3.1.6	Acceptance criteria .....	43
5.2.3.2	Electrical tests on contact C2: 1,8 V - 3 V .....	44
5.2.3.2.1	Definition and applicability .....	44
5.2.3.2.2	Conformance requirement .....	44
5.2.3.2.3	Reference.....	44
5.2.3.2.4	Test purpose .....	44
5.2.3.2.5	Method of test.....	44
5.2.3.2.6	Acceptance criteria .....	44
5.2.4	Electrical tests on contact C3 (Clock - CLK) .....	44
5.2.4.1	Electrical tests on contact C3: 3 V - 5 V .....	44
5.2.4.1.1	Definition and applicability .....	44

5.2.4.1.2	Conformance requirement .....	45
5.2.4.1.3	Reference .....	45
5.2.4.1.4	Test purpose .....	45
5.2.4.1.5	Method of test.....	45
5.2.4.1.6	Acceptance criteria .....	45
5.2.4.2	Electrical tests on contact C3: 1,8 V - 3 V .....	46
5.2.4.2.1	Definition and applicability .....	46
5.2.4.2.2	Conformance requirement .....	46
5.2.4.2.3	Reference .....	46
5.2.4.2.4	Test purpose .....	46
5.2.4.2.5	Method of test.....	46
5.2.4.2.6	Acceptance criteria .....	47
5.2.5	Electrical tests on contact C7 (Input/Output - I/O) .....	47
5.2.5.1	Electrical tests on contact C7, Test 1: 3 V - 5 V .....	47
5.2.5.1.1	Definition and applicability .....	47
5.2.5.1.2	Conformance requirement .....	47
5.2.5.1.3	Reference .....	48
5.2.5.1.4	Test purpose .....	48
5.2.5.1.5	Method of test.....	48
5.2.5.1.6	Acceptance criteria .....	48
5.2.5.2	Electrical tests on contact C7, Test 2: 3 V - 5 V .....	48
5.2.5.2.1	Definition and applicability .....	48
5.2.5.2.2	Conformance requirement .....	48
5.2.5.2.3	Reference .....	49
5.2.5.2.4	Test purpose .....	49
5.2.5.2.5	Method of test.....	49
5.2.5.2.6	Acceptance criteria .....	49
5.2.5.3	Electrical tests on contact C7, Test 1: 1,8 V - 3 V .....	49
5.2.5.3.1	Definition and applicability .....	49
5.2.5.3.2	Conformance requirement .....	50
5.2.5.3.3	Reference .....	50
5.2.5.3.4	Test purpose .....	50
5.2.5.3.5	Method of test.....	50
5.2.5.3.6	Acceptance criteria .....	51
5.2.5.4	Electrical tests on contact C7, Test 2: 1,8 V - 3 V .....	51
5.2.5.4.1	Definition and applicability .....	51
5.2.5.4.2	Conformance requirement .....	51
5.2.5.4.3	Reference .....	51
5.2.5.4.4	Test purpose .....	51
5.2.5.4.5	Method of test.....	52
5.2.5.4.6	Acceptance criteria .....	52
6	Initial communication tests .....	52
6.1	ATR.....	52
6.1.1	ATR characters .....	52
6.1.1.1	Definition and applicability.....	52
6.1.1.2	Conformance requirement.....	52
6.1.1.2.0	Description .....	52
6.1.1.2.1	Reference.....	52
6.1.1.3	Test purpose .....	53
6.1.1.4	Method of test .....	53
6.1.1.4.1	Initial conditions .....	53
6.1.1.4.2	Procedure.....	53
6.1.1.5	Acceptance criteria.....	56
6.2	Clock stop mode with 1,8 V technology UICC.....	56
6.2.1	Definition and applicability .....	56
6.2.2	Conformance requirement .....	56
6.2.2.0	Description .....	56
6.2.2.1	Reference .....	56
6.2.3	Test purpose.....	56
6.2.4	Method of test .....	56
6.2.4.1	Initial conditions .....	56

6.2.4.2	Procedure .....	57
6.2.5	Acceptance criteria .....	58
6.3	Clock stop mode with 3 V technology UICC .....	59
6.3.1	Definition and applicability .....	59
6.3.2	Conformance requirement .....	59
6.3.2.0	Description .....	59
6.3.2.1	Reference .....	59
6.3.3	Test purpose .....	59
6.3.4	Method of test .....	59
6.3.4.1	Initial conditions .....	59
6.3.4.2	Procedure .....	59
6.3.5	Acceptance criteria .....	61
6.4	Void .....	61
6.5	Speed enhancement .....	61
6.5.1	Definition and applicability .....	61
6.5.2	Conformance requirement .....	62
6.5.3	Test purpose .....	62
6.5.4	Method of test .....	62
6.5.4.1	Initial conditions .....	62
6.5.4.2	Procedure .....	62
6.5.5	Acceptance criteria .....	63
7	Transmission protocol tests .....	63
7.1	Character transmission .....	63
7.1.1	Bit/character duration during the transmission from the Terminal to the UICC .....	63
7.1.1.1	Definition and applicability .....	63
7.1.1.2	Conformance requirement .....	63
7.1.1.2.0	Description .....	63
7.1.1.2.1	Reference .....	63
7.1.1.3	Test purpose .....	64
7.1.1.4	Method of test .....	64
7.1.1.4.1	Initial conditions .....	64
7.1.1.4.2	Procedure .....	64
7.1.1.5	Acceptance criteria .....	64
7.1.2	Bit/character duration during the transmission from the UICC to the Terminal .....	64
7.1.2.1	Definition and applicability .....	64
7.1.2.2	Conformance requirement .....	64
7.1.2.2.0	Description .....	64
7.1.2.2.1	Reference .....	64
7.1.2.3	Test purpose .....	64
7.1.2.4	Method of test .....	64
7.1.2.4.1	Initial conditions .....	64
7.1.2.4.2	Procedure .....	65
7.1.2.5	Acceptance criteria .....	65
7.2	T=0 protocol .....	65
7.2.1	Timing .....	65
7.2.1.1	Definition and applicability .....	65
7.2.1.2	Conformance requirement .....	65
7.2.1.2.0	Description .....	65
7.2.1.2.1	Reference .....	65
7.2.1.3	Test purpose .....	65
7.2.1.4	Method of test .....	65
7.2.1.4.1	Initial conditions .....	65
7.2.1.4.2	Procedure .....	66
7.2.1.5	Acceptance criteria .....	66
7.2.2	Command processing, ACK, NACK, NULL procedure bytes .....	67
7.2.2.1	Definition and applicability .....	67
7.2.2.2	Conformance requirement .....	67
7.2.2.2.0	Description .....	67
7.2.2.2.1	Reference .....	67
7.2.2.3	Test purpose .....	67
7.2.2.4	Method of test .....	67



7.2.2.4.1	Initial conditions .....	67
7.2.2.4.2	Procedure .....	67
7.2.2.5	Acceptance criteria .....	68
7.2.3	Case 2 command, use of procedure bytes '61xx' and '6Cxx' .....	68
7.2.3.1	Definition and applicability .....	68
7.2.3.2	Conformance requirement .....	68
7.2.3.2.0	Description .....	68
7.2.3.2.1	Reference .....	68
7.2.3.3	Test purpose .....	68
7.2.3.4	Method of test .....	68
7.2.3.4.1	Initial conditions .....	68
7.2.3.4.2	Procedure .....	68
7.2.3.5	Acceptance criteria .....	68
7.2.4	Case 4 command, use of procedure bytes '61xx' .....	69
7.2.4.1	Definition and applicability .....	69
7.2.4.2	Conformance requirement .....	69
7.2.4.2.0	Description .....	69
7.2.4.2.1	Reference .....	69
7.2.4.3	Test purpose .....	69
7.2.4.4	Method of test .....	69
7.2.4.4.1	Initial conditions .....	69
7.2.4.4.2	Procedure .....	69
7.2.4.5	Acceptance criteria .....	69
7.2.5	Command processing, warning and error status bytes .....	70
7.2.5.1	Definition and applicability .....	70
7.2.5.2	Conformance requirement .....	70
7.2.5.2.0	Description .....	70
7.2.5.2.1	Reference .....	70
7.2.5.3	Test purpose .....	70
7.2.5.4	Method of test .....	70
7.2.5.4.1	Initial conditions .....	70
7.2.5.4.2	Procedure .....	70
7.2.5.5	Acceptance criteria .....	70
7.2.6	Error correction .....	71
7.2.6.1	Definition and applicability .....	71
7.2.6.2	Conformance requirement .....	71
7.2.6.2.0	Description .....	71
7.2.6.2.1	Reference .....	71
7.2.6.3	Test purpose .....	71
7.2.6.4	Method of test .....	71
7.2.6.4.1	Initial conditions .....	71
7.2.6.4.2	Procedure .....	71
7.2.6.5	Acceptance criteria .....	71
7.2.7	Error detection .....	71
7.2.7.1	Definition and applicability .....	71
7.2.7.2	Conformance requirement .....	71
7.2.7.2.0	Description .....	71
7.2.7.2.1	Reference .....	72
7.2.7.3	Test purpose .....	72
7.2.7.4	Method of test .....	72
7.2.7.4.1	Initial conditions .....	72
7.2.7.4.2	Procedure .....	72
7.2.7.5	Acceptance criteria .....	72
7.3	T=1 protocol .....	72
7.3.1	Character Waiting Time .....	72
7.3.1.1	Definition and applicability .....	72
7.3.1.2	Conformance requirement .....	72
7.3.1.2.0	Description .....	72
7.3.1.2.1	Reference .....	72
7.3.1.3	Test purpose .....	72
7.3.1.4	Method of test .....	72
7.3.1.4.1	Initial conditions .....	72



7.3.1.4.2	Procedure.....	73
7.3.1.5	Acceptance criteria.....	73
7.3.2	Block Timing.....	73
7.3.2.1	Definition and applicability.....	73
7.3.2.2	Conformance requirement.....	74
7.3.2.2.0	Description.....	74
7.3.2.2.1	Reference.....	74
7.3.2.3	Test purpose.....	74
7.3.2.4	Method of test.....	74
7.3.2.4.1	Initial conditions.....	74
7.3.2.4.2	Procedure.....	74
7.3.2.5	Acceptance criteria.....	75
7.3.3	Block Waiting Time extension.....	75
7.3.3.1	Definition and applicability.....	75
7.3.3.2	Conformance requirement.....	75
7.3.3.2.0	Description.....	75
7.3.3.2.1	Reference.....	75
7.3.3.3	Test purpose.....	75
7.3.3.4	Method of test.....	76
7.3.3.4.1	Initial conditions.....	76
7.3.3.4.2	Procedure.....	76
7.3.3.5	Acceptance criteria.....	77
7.3.4	Chaining - Respect of IFSC by Terminal.....	77
7.3.4.1	Definition and applicability.....	77
7.3.4.2	Conformance requirement.....	77
7.3.4.2.0	Description.....	77
7.3.4.2.1	Reference.....	77
7.3.4.3	Test purpose.....	77
7.3.4.4	Method of test.....	77
7.3.4.4.1	Initial conditions.....	77
7.3.4.4.2	Procedure.....	78
7.3.4.5	Acceptance criteria.....	79
7.3.5	Chaining - IFSD management.....	79
7.3.5.1	Definition and applicability.....	79
7.3.5.2	Conformance requirement.....	79
7.3.5.2.0	Description.....	79
7.3.5.2.1	Reference.....	79
7.3.5.3	Test purpose.....	79
7.3.5.4	Method of test.....	79
7.3.5.4.1	Initial conditions.....	79
7.3.5.4.2	Procedure.....	80
7.3.5.5	Acceptance criteria.....	80
7.3.6	I-Block error correction.....	80
7.3.6.1	Definition and applicability.....	80
7.3.6.2	Conformance requirement.....	80
7.3.6.2.0	Description.....	80
7.3.6.2.1	Reference.....	80
7.3.6.3	Test purpose.....	80
7.3.6.4	Method of test.....	80
7.3.6.4.1	Initial conditions.....	80
7.3.6.4.2	Procedure.....	81
7.3.6.5	Acceptance criteria.....	81
7.3.7	I-Block error detection.....	81
7.3.7.1	Definition and applicability.....	81
7.3.7.2	Conformance requirement.....	81
7.3.7.2.0	Description.....	81
7.3.7.2.1	Reference.....	81
7.3.7.3	Test purpose.....	81
7.3.7.4	Method of test.....	81
7.3.7.4.1	Initial conditions.....	81
7.3.7.4.2	Procedure.....	81
7.3.7.5	Acceptance criteria.....	82

7.3.8	R-Block error handling in non-chaining mode .....	82
7.3.8.1	Definition and applicability.....	82
7.3.8.2	Conformance requirement.....	82
7.3.8.2.0	Description .....	82
7.3.8.2.1	Reference.....	82
7.3.8.3	Test purpose .....	82
7.3.8.4	Method of test .....	82
7.3.8.4.1	Initial conditions.....	82
7.3.8.4.2	Procedure.....	83
7.3.8.5	Acceptance criteria.....	83
7.3.9	R-Block error handling in chaining mode.....	83
7.3.9.1	Definition and applicability.....	83
7.3.9.2	Conformance requirement.....	83
7.3.9.2.0	Description .....	83
7.3.9.2.1	Reference.....	83
7.3.9.3	Test purpose .....	83
7.3.9.4	Method of test .....	84
7.3.9.4.1	Initial conditions.....	84
7.3.9.4.2	Procedure.....	84
7.3.9.5	Acceptance criteria.....	84
7.3.10	Successive errors in both directions.....	84
7.3.10.1	Definition and applicability.....	84
7.3.10.2	Conformance requirement.....	84
7.3.10.2.0	Description .....	84
7.3.10.2.1	Reference.....	84
7.3.10.3	Test purpose .....	85
7.3.10.4	Method of test .....	85
7.3.10.4.1	Initial conditions.....	85
7.3.10.4.2	Procedure.....	85
7.3.10.5	Acceptance criteria.....	85
7.3.11	Chaining - Abortion .....	85
7.3.11.1	Definition and applicability.....	85
7.3.11.2	Conformance requirement.....	86
7.3.11.2.0	Description .....	86
7.3.11.2.1	Reference.....	86
7.3.11.3	Test purpose .....	86
7.3.11.4	Method of test .....	86
7.3.11.4.1	Initial conditions.....	86
7.3.11.4.2	Procedure.....	86
7.3.11.5	Acceptance criteria.....	86
7.3.12	Block repetition and resynchronization .....	87
7.3.12.1	Definition and applicability.....	87
7.3.12.2	Conformance requirement.....	87
7.3.12.2.0	Description .....	87
7.3.12.2.1	Reference.....	87
7.3.12.3	Test purpose .....	87
7.3.12.4	Method of test .....	87
7.3.12.4.1	Initial conditions.....	87
7.3.12.4.2	Procedure.....	87
7.3.12.5	Acceptance criteria.....	88
7.3.13	UICC is unresponsive .....	88
7.3.13.1	Definition and applicability.....	88
7.3.13.2	Conformance requirement.....	88
7.3.13.2.0	Description .....	88
7.3.13.2.1	Reference.....	89
7.3.13.3	Test purpose .....	89
7.3.13.4	Method of test .....	89
7.3.13.4.1	Initial conditions.....	89
7.3.13.4.2	Procedure.....	89
7.3.13.5	Acceptance criteria.....	89
8	Application dependent procedures .....	90

8.1	UICC presence detection .....	90
8.1.1	Definition and applicability .....	90
8.1.2	Conformance requirement .....	90
8.1.2.0	Description .....	90
8.1.2.1	Reference .....	90
8.1.3	Test purpose .....	90
8.1.4	Method of test .....	90
8.1.4.1	Initial conditions .....	90
8.1.4.2	Procedure .....	90
8.1.5	Acceptance criteria .....	91
9	Commands .....	91
9.1	TERMINAL CAPABILITY .....	91
9.1.1	Additional interfaces support .....	91
9.1.1.1	Definition and applicability .....	91
9.1.1.2	Conformance requirement .....	91
9.1.1.2.1	Description .....	91
9.1.1.2.2	Reference .....	91
9.1.1.3	Test purpose .....	91
9.1.1.4	Method of test .....	91
9.1.1.4.1	Initial conditions .....	91
9.1.1.4.2	Procedure .....	92
9.1.1.5	Acceptance criteria .....	92
<b>Annex A (normative):</b>	<b>UICC simulator functional requirement .....</b>	<b>93</b>
A.1	General .....	93
A.2	Contacts C1, C3, C7 .....	93
A.2.1	Default measurement/setting uncertainties .....	93
A.2.2	Contact C1 .....	93
A.2.3	Contact C7 .....	94
A.2.4	Contact C3 .....	94
A.3	Definition of timing .....	94
<b>Annex B (informative):</b>	<b>Change history .....</b>	<b>95</b>
History	.....	96

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# Foreword

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The present document is part 1 of a multi-part deliverable covering the UICC-Terminal interface; Physical, electrical and logical test specification, as identified below:

Part 1: "Terminal features";

Part 2: "UICC features".

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# Modal verbs terminology

In the present document "**shall**", "**shall not**", "**should**", "**should not**", "**may**", "**need not**", "**will**", "**will not**", "**can**" and "**cannot**" are to be interpreted as described in clause 3.2 of the [ETSI Drafting Rules](#) (Verbal forms for the expression of provisions).

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# Introduction

The present document defines the interface tests for the Terminal/UICC interface.

The aim of the present document is to ensure interoperability between an UICC and a Terminal independently of the respective manufacturer, card issuer or operator.

Application specific tests for applications residing on an UICC are specified in ETSI TS 131 121 [4].

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